

LIST OF PRIOR ART CITED BY APPLICANT							
(PTO-1449)			ATTY. DOCKET NO. P-0483		APPLN. SERIAL NO. 10/624,524		
APPLICANT(S) Yong-Hee LEE and Joon JANG							
FILING DATE July 23, 2003					GROUP 2612		
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE	
U.S. PATENT APPLICATION PUBLICATIONS							
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS		
U.S. PATENT APPLICATIONS							
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No	
NT	10-2004-0006710	1/24/04	KOREA	-	-	Part. Abst	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)							
NT	Korean Office Action dated July 28, 2004						
EXAMINER				DATE CONSIDERED			
/Nhan Tran/				11/03/2006			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant. DYK/RAV:knv

DYK/RAV:knv

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(PTO-1449)**

ATTY. DOCKET NO.
P-0483

APPLN. SERIAL NO.
10/624,524

APPLICANT(S)
Yong-Hee LEE and Joon JANG

FILING DATE
July 23, 2003

GROUP
UNKNOWN

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
NT	5,537,175	7/16/96	Kamaya et al.	—	—	

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
NT	2001/0038412 A1	11/8/2001	McNelley et al.	//	//	
NT	2002/0051060 A1	5/2/2002	Wada	//	//	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

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EXAMINER /Nhan Tran/

DATE CONSIDERED 11/03/2006

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[illegible]

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